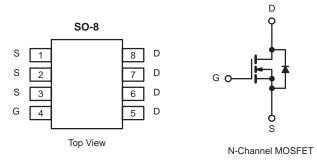


N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^a	Q _g (Typ.)			
30	0.016 at V _{GS} = 10 V	6.8	9.2 nC			
	0.029 at V _{GS} = 4.5 V	5.8				



FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- Compliant to RoHS Directive 2002/95/EC

RoHS COMPLIANT HALOGEN

APPLICATIONS

- · Notebook Load Switch
- Low Current dc-to-dc

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	30	V	
Gate-Source Voltage	V _{GS}	± 20	V	
	T _C = 25 °C		6.8 ^a	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	1 , 🗀	5 ^a	
Continuous Diam Curient (1) = 130 °C)	T _A = 25 °C	l _D	6.5 ^{b,c}	
	T _A = 70 °C		4.9 ^{b,c}	Α
Pulsed Drain Current	I _{DM}	30		
Continuous Course Drain Diade Current	T _C = 25 °C		2.7	
Continuous Source-Drain Diode Current	T _A = 25 °C	l _s –	1.7 ^{b,c}	
	T _C = 25 °C		4.1	
Mayimum Dawar Dissination	T _C = 70 °C		2.6	w
Maximum Power Dissipation	T _A = 25 °C	P _D	2 ^{b,c}	VV
	T _A = 70 °C		1.25 ^{b,c}	
Operating Junction and Storage Temperature Rang	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter	Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R_{thJA}	45	62.5	°C/W	
Maximum Junction-to-Foot	Steady State	R_{thJF}	25	30	- "C/VV	

Notes

- a. Package Limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 5 s
- d. Maximum under Steady State conditions is 110 °C/W.



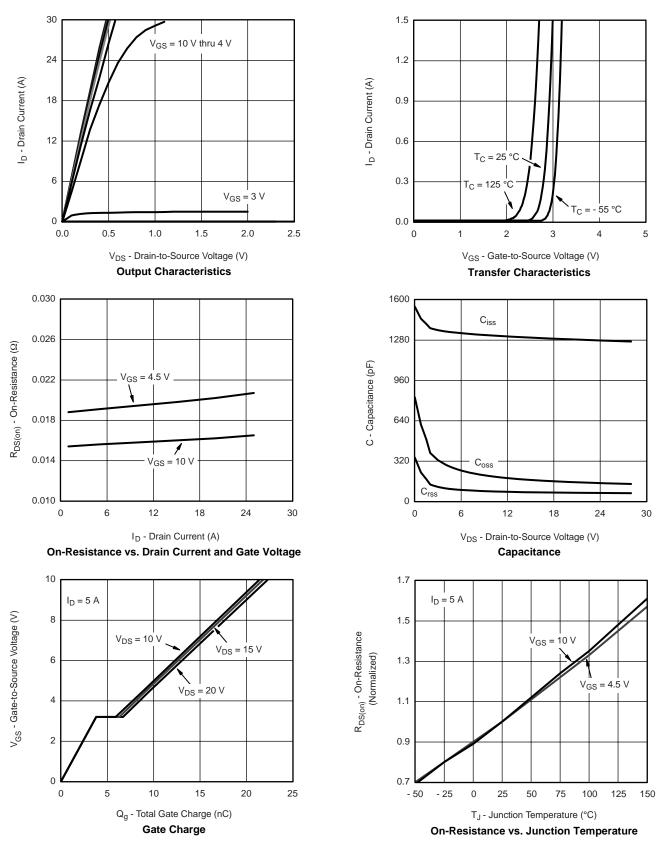
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static						L	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V, } I_D = 250 \mu\text{A}$	30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250A		33		1/04	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6.2		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1		3	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
7 0 1 1/1 1 0 1	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$		1			
Zero Gate Voltage Drain Current		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	V _{DS} ≥ 5 V, V _{GS} = 10 V	20			Α	
	_	$V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$	0.016 0.029			Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 4 \text{ A}$					
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 10 \text{ V}, I_D = 5 \text{ A}$		24		S	
Dynamic ^b	1						
Input Capacitance	C _{iss}			1295		pF	
Output Capacitance	C _{oss}	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		170			
Reverse Transfer Capacitance	C _{rss}			72			
Total Gate Charge		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		21.8	33	nC	
				9.2	14		
Gate-Source Charge	Q_{gs}	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 5 \text{ A}$		3.8			
Gate-Drain Charge	Q _{gd}			2.5			
Gate Resistance	R_{g}	f = 1 MHz		2.4		Ω	
Turn-On Delay Time	t _{d(on)}			21	40		
Rise Time	ì,	V_{DD} = 15 V, R_L = 3 Ω		14	25		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		20	40		
Fall Time	t _f	-		9	18		
Turn-On Delay Time	t _{d(on)}			10	20	ns	
Rise Time	ì,	V_{DD} = 15 V, R_L = 3 Ω		8	16	-	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		21	35		
Fall Time	t _f	-		8	16		
Drain-Source Body Diode Characterist	ics						
Continous Source-Drain Diode Current	I _S	T _C = 25 °C			2.7	_	
Pulse Diode Forward Current	I _{SM}				30	Α	
Body Diode Voltage	V_{SD}	$I_S = 1.7 \text{ A}, V_{GS} = 0 \text{ V}$		0.77	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			21	40	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I = 2 A dl/dt = 100 A/::2 T = 05 °C		15	30	nC	
Reverse Recovery Fall Time t _a		$I_F = 3 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		13			
Reverse Recovery Rise Time	t _b			8		ns	

Notes:

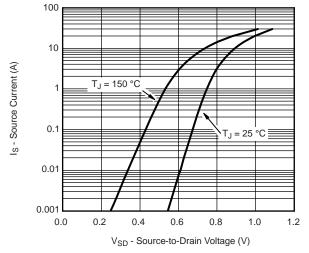
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

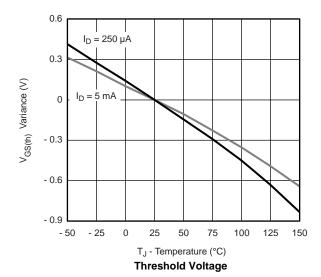


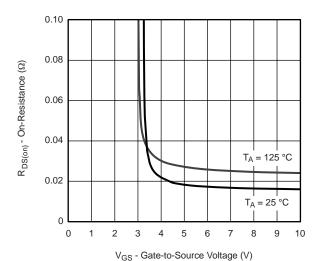




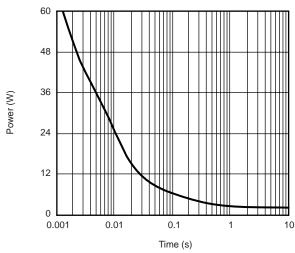


Source-Drain Diode Forward Voltage

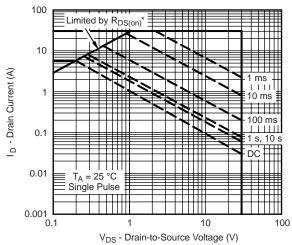




On-Resistance vs. Gate-to-Source Temperature



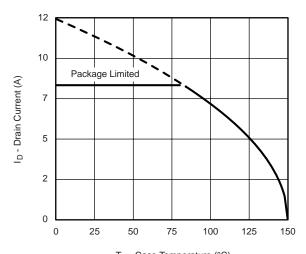
Single Pulse Power, Junction-to-Ambient



* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

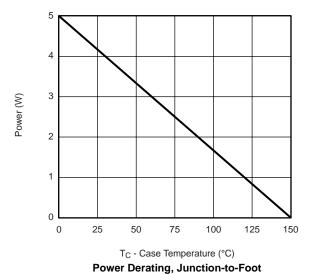
Safe Operating Area, Junction-to-Ambient

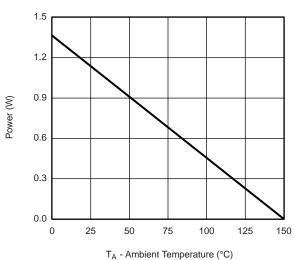




T_C - Case Temperature (°C)

Current Derating*

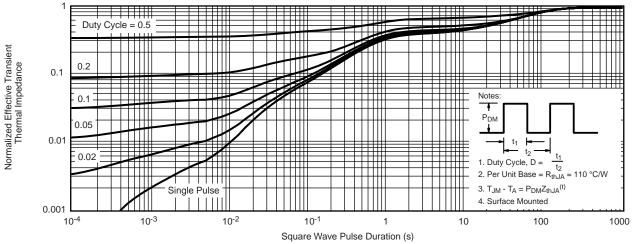




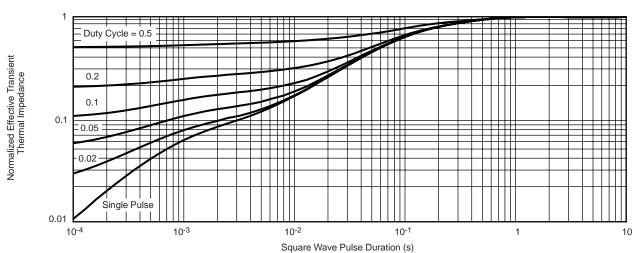
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient

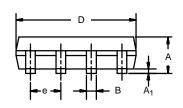


Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







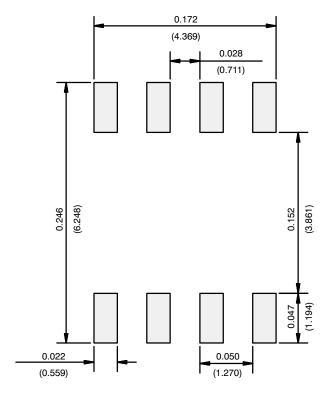
	MILLIMETERS		INC	HES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050 BSC			
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
FCN: C-06527-Rev 11-Sen-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

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